

## N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY	
$V_{DS}$ (V) at $T_J$ max.	650
$R_{DS(on)}$ max. at 25 °C ( $\Omega$ )	$V_{GS} = 10$ V      0.58
$Q_g$ max. (nC)	43
$Q_{gs}$ (nC)	5
$Q_{gd}$ (nC)	22
Configuration	Single

### FEATURES

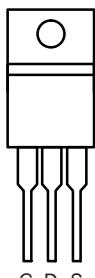
- Low figure-of-merit (FOM)  $R_{on} \times Q_g$
- Low input capacitance ( $C_{iss}$ )
- Reduced switching and conduction losses
- Ultra low gate charge ( $Q_g$ )
- Avalanche energy rated (UIS)



### APPLICATIONS

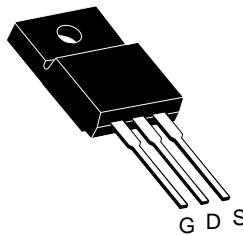
- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial

TO-220AB

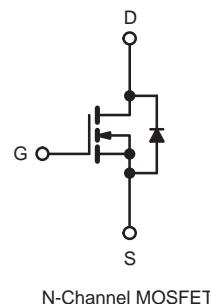


Top View

TO-220 FULLPAK



Top View



N-Channel MOSFET

### ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	$V_{DS}$	650	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	
Continuous Drain Current ( $T_J = 150$ °C)	$I_D$ at 10 V	12	A
		9.4	
Pulsed Drain Current <sup>a</sup>	$I_{DM}$	45	
Linear Derating Factor		3.6	W/°C
Single Pulse Avalanche Energy <sup>b</sup>	$E_{AS}$	290	mJ
Maximum Power Dissipation	$P_D$	106 /34	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 to +150	°C
Drain-Source Voltage Slope	$dV/dt$	15	V/ns
Reverse Diode $dV/dt$ <sup>d</sup>		4.1	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s	300	°C

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50$  V, starting  $T_J = 25$  °C,  $L = 28.2$  mH,  $R_g = 25$  Ω,  $I_{AS} = 4.5$  A.
- 1.6 mm from case.
- $I_{SD} \leq I_D$ ,  $dI/dt = 100$  A/μs, starting  $T_J = 25$  °C.

**THERMAL RESISTANCE RATINGS**

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	60	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8	

**SPECIFICATIONS** ( $T_J = 25^{\circ}\text{C}$ , unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$		650	-	-	V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25^{\circ}\text{C}$ , $I_D = 1 \text{ mA}$		-	0.75	-	$\text{V}/^{\circ}\text{C}$
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$		2	-	4	V
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20 \text{ V}$		-	-	$\pm 100$	nA
		$V_{GS} = \pm 30 \text{ V}$		-	-	$\pm 1$	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 650 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	-	1	$\mu\text{A}$
		$V_{DS} = 520 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 125^{\circ}\text{C}$		-	-	10	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 8 \text{ A}$	-	0.58	-	$\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 30 \text{ V}$ , $I_D = 8 \text{ A}$		-	16	-	S
<b>Dynamic</b>							
Input Capacitance	$C_{iss}$	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 100 \text{ V}$ , $f = 1 \text{ MHz}$		-	2200	-	pF
Output Capacitance	$C_{oss}$			-	420	-	
Reverse Transfer Capacitance	$C_{rss}$			-	210	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	$C_{o(er)}$	$V_{DS} = 0 \text{ V}$ to $520 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	63	-	
Effective Output Capacitance, Time Related <sup>b</sup>	$C_{o(tr)}$			-	213	-	
Total Gate Charge	$Q_g$			-	43	-	nC
Gate-Source Charge	$Q_{gs}$	$V_{GS} = 10 \text{ V}$	$I_D = 8 \text{ A}$ , $V_{DS} = 520 \text{ V}$	-	5	-	
Gate-Drain Charge	$Q_{gd}$			-	22	-	
Turn-On Delay Time	$t_{d(on)}$			-	13	-	ns
Rise Time	$t_r$	$V_{DD} = 520 \text{ V}$ , $I_D = 8 \text{ A}$ , $V_{GS} = 10 \text{ V}$ , $R_g = 9.1 \Omega$		-	11	-	
Turn-Off Delay Time	$t_{d(off)}$			-	81	-	
Fall Time	$t_f$			-	25	-	
Gate Input Resistance	$R_g$	$f = 1 \text{ MHz}$ , open drain		-	3.5	-	$\Omega$
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	A
Pulsed Diode Forward Current	$I_{SM}$			-	-	40	
Diode Forward Voltage	$V_{SD}$	$T_J = 25^{\circ}\text{C}$ , $I_S = 8 \text{ A}$ , $V_{GS} = 0 \text{ V}$		-	-	1.5	V
Reverse Recovery Time	$t_{rr}$	$T_J = 25^{\circ}\text{C}$ , $I_F = I_S = 8 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_R = 400 \text{ V}$		-	345	-	ns
Reverse Recovery Charge	$Q_{rr}$			-	4.5	-	$\mu\text{C}$
Reverse Recovery Current	$I_{RRM}$			-	35	-	A

**Notes**

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .  
 b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

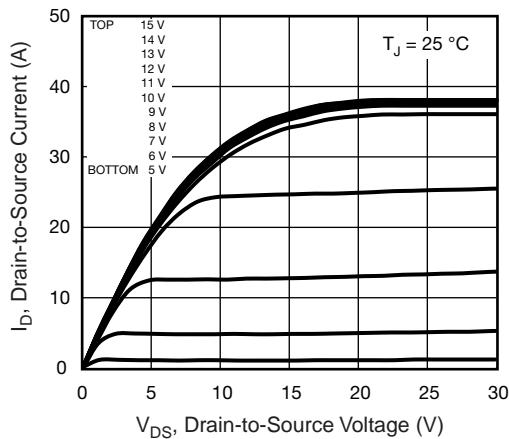
**TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics

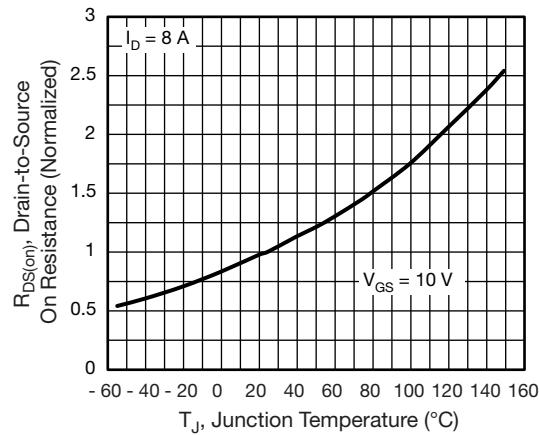


Fig. 4 - Normalized On-Resistance vs. Temperature

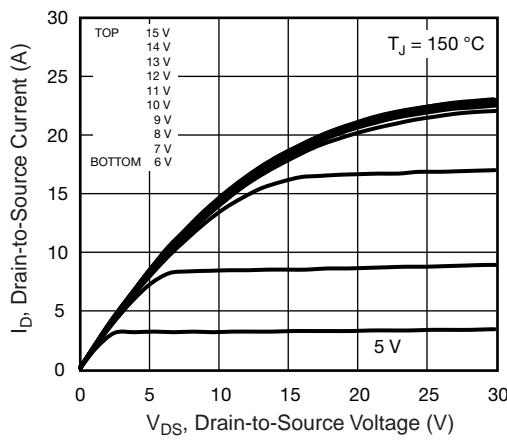


Fig. 2 - Typical Output Characteristics

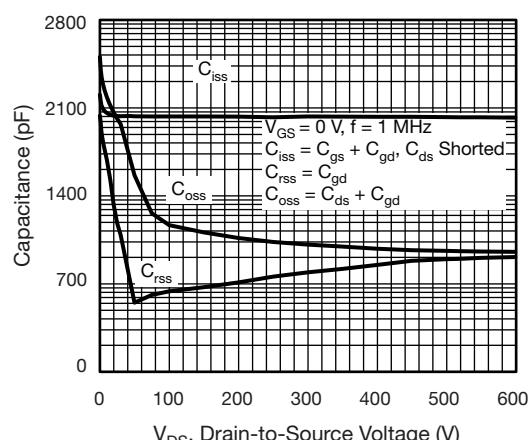


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

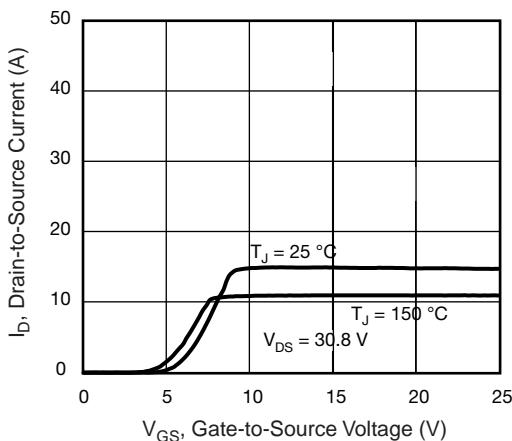


Fig. 3 - Typical Transfer Characteristics

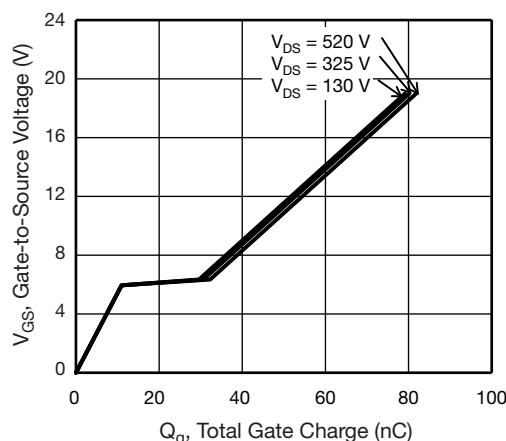


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

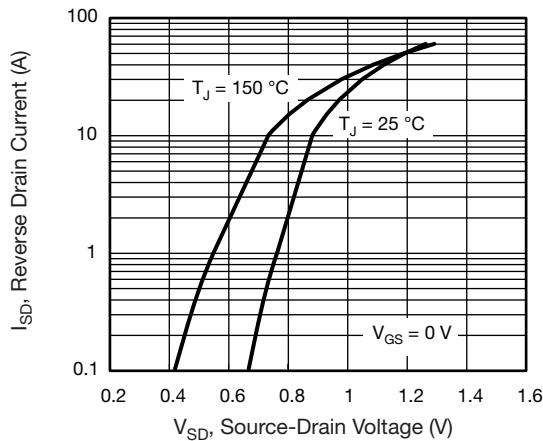


Fig. 7 - Typical Source-Drain Diode Forward Voltage

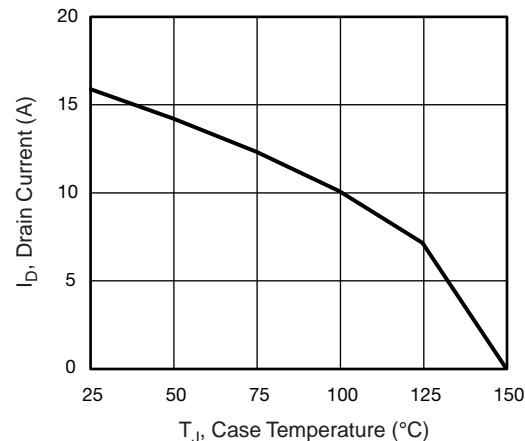


Fig. 9 - Maximum Drain Current vs. Case Temperature

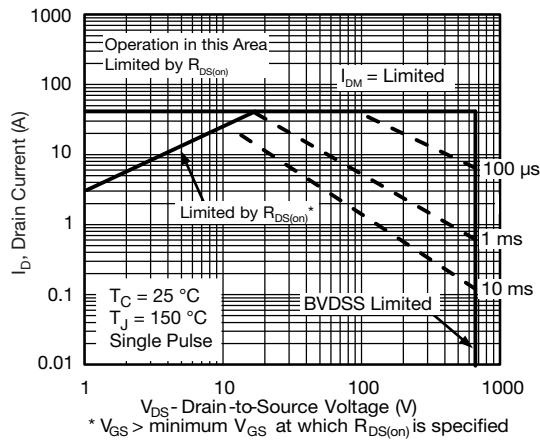


Fig. 8 - Maximum Safe Operating Area

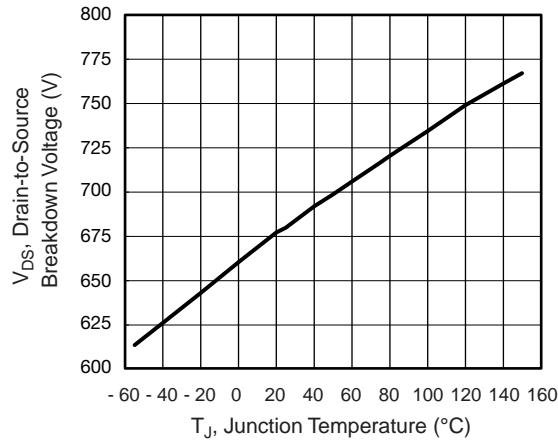


Fig. 10 - Temperature vs. Drain-to-Source Voltage

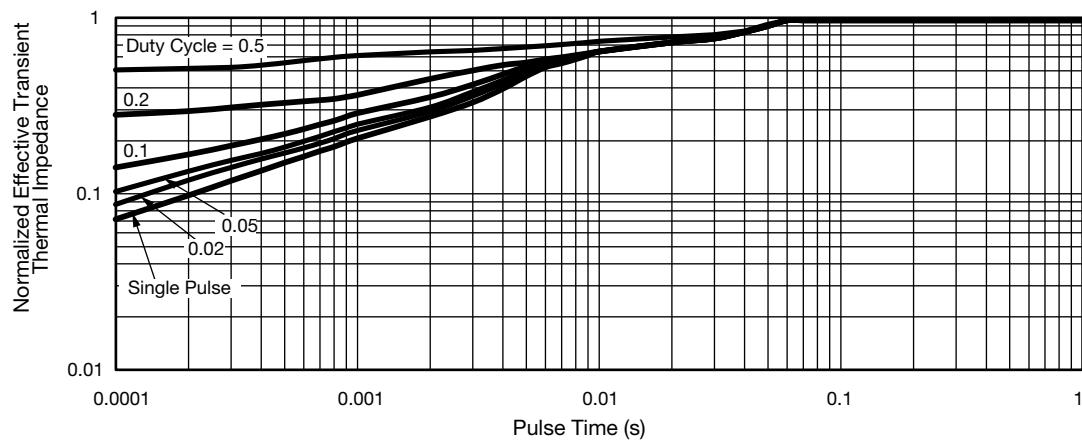


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

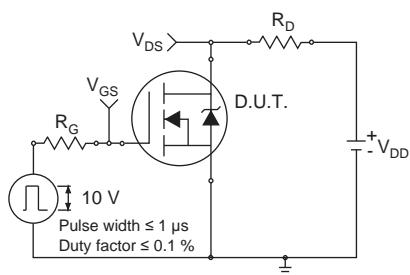


Fig. 12 - Switching Time Test Circuit

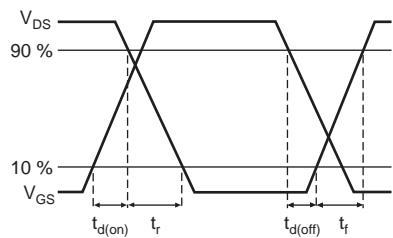


Fig. 13 - Switching Time Waveforms

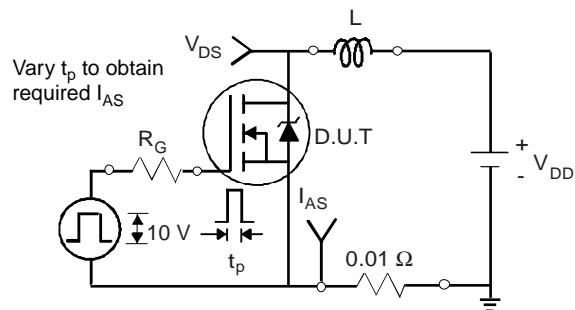


Fig. 14 - Unclamped Inductive Test Circuit

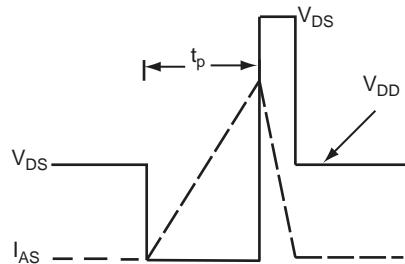


Fig. 15 - Unclamped Inductive Waveforms

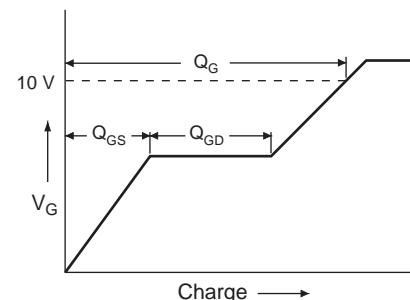


Fig. 16 - Basic Gate Charge Waveform

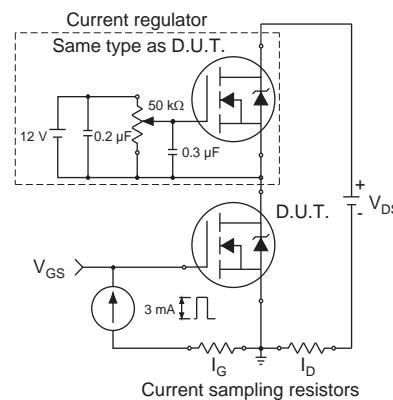
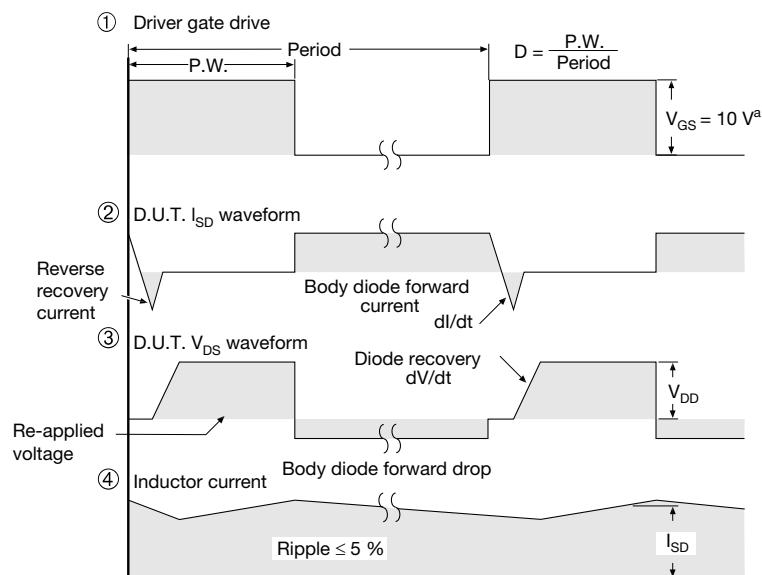
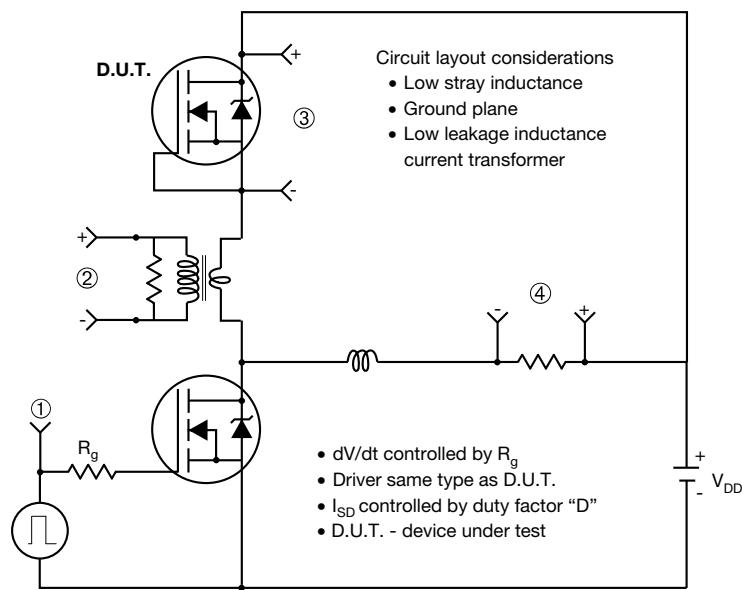


Fig. 17 - Gate Charge Test Circuit

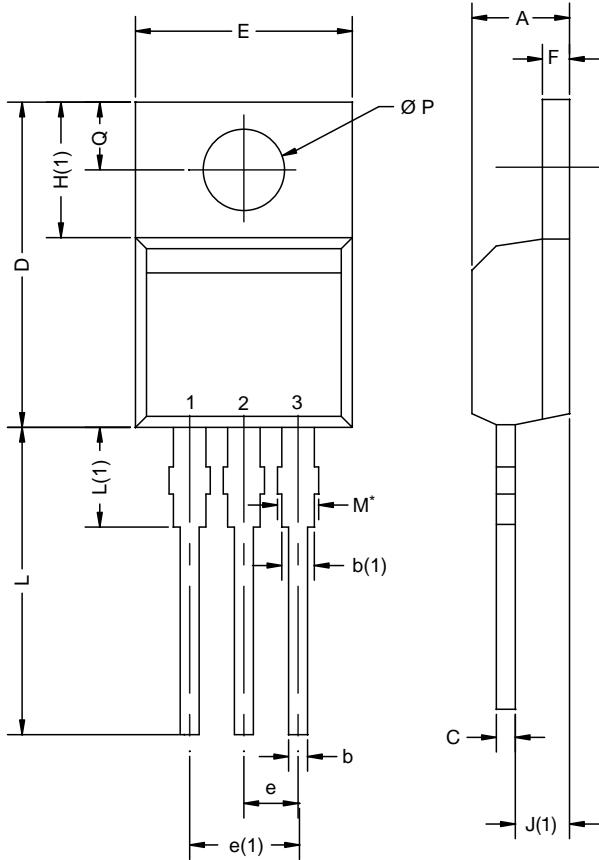
### Peak Diode Recovery dV/dt Test Circuit



**Note**

a.  $V_{GS} = 5 \text{ V}$  for logic level devices

Fig. 18 - For N-Channel

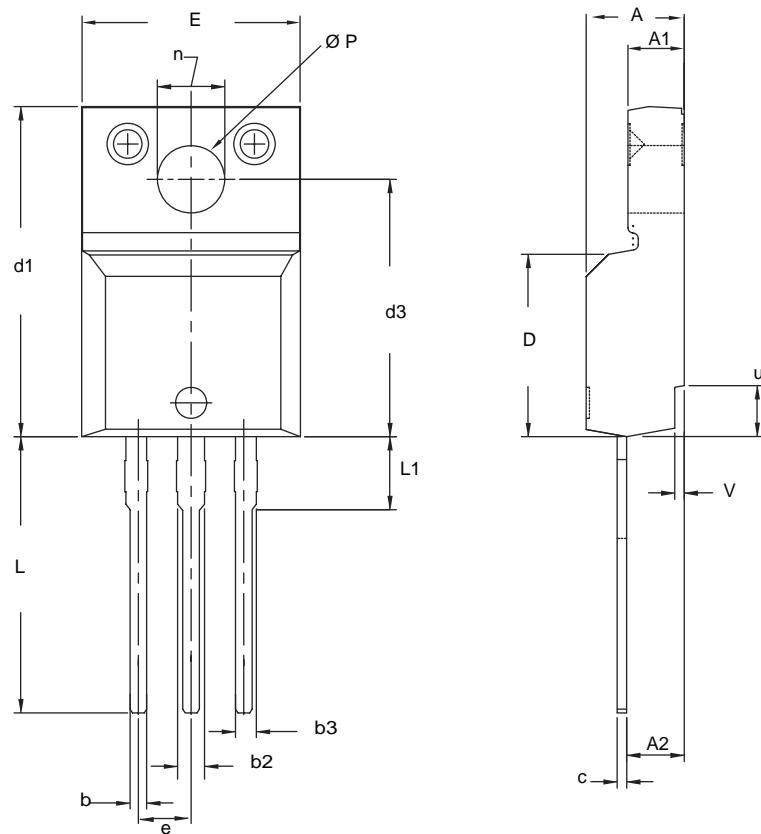
**TO-220AB**

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØP	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

ECN: X12-0208-Rev. N, 08-Oct-12  
DWG: 5471

**Notes**

\* M = 1.32 mm to 1.62 mm (dimension including protrusion)  
Heatsink hole for HVM

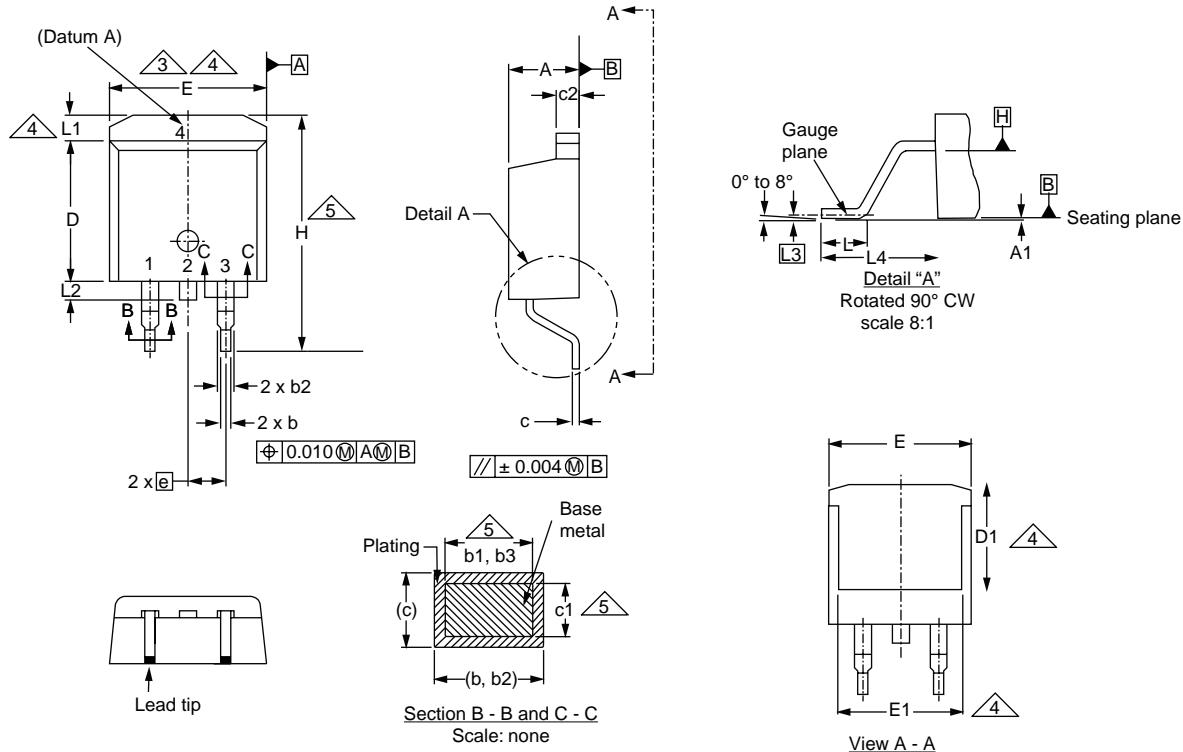
**TO-220 FULLPAK (HIGH VOLTAGE)**

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
c	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
e	2.54 BSC		0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
Ø P	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
v	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09  
 DWG: 5972

**Notes**

1. To be used only for process drawing.
2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
3. All critical dimensions should C meet  $C_{pk} > 1.33$ .
4. All dimensions include burrs and plating thickness.
5. No chipping or package damage.

**TO-263AB (HIGH VOLTAGE)**

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
c	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

ECN: S-82110-Rev. A, 15-Sep-08  
DWG: 5970

**Notes**

- Dimensioning and tolerancing per ASME Y14.5M-1994.
- Dimensions are shown in millimeters (inches).
- Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- Thermal PAD contour optional within dimension E, L1, D1 and E1.
- Dimension b1 and c1 apply to base metal only.
- Datum A and B to be determined at datum plane H.
- Outline conforms to JEDEC outline to TO-263AB.

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